OIP	PTO-14	49								COMMERCE RK OFFICE		Y. DOCKET NO. 5565			AL NO. 34,746		
) MAD a -	INFO	RMAT	NOI	DI	SCL	osu	RE	CIT	AT]	ON		LICANT ung-Jin Park et	al				
MAR 2 3	A11124 : 1	seve	ral	sh	eet	s i	f n	ece	888	ary)	FIL	ING DATE	<u>u. </u>	GROU	Þ	- -	
& .	Ø									•	P	ugust 6, 2003		 			
A JRADEMA	BYNATION	· ·	1							U.S. PATE	NT D	CUMENTS		· · · · · · ·	r . — · · · · · ·		
	EXAMINER INITIAL		DO	CUM	ENT	N	JMBE	R		DATE		NAME		CLASS	SUBCL ASS	i	NG DATE IP OPRIATE
	. ,																
									Г								
			<u> </u>					<u> </u>	T			· · · · · · · · · · · · · · · · · · ·					
		<u> </u>					ļ	 .			 						
		-	·		_			/ .	-	<u> </u>			_				
			\vdash				Z		-		-	•	•				•
									Ė		-					<u> </u>	
				\neq					_	 	 			· · · · · ·			
•	 							<u> </u>					\dashv				
			1	ليا	L:	Ш		<u> </u>	ļ	<u></u>	<u>. </u>					L	
,			т -				:	PUB	LIS	HED U.S. P	ATEN	T APPLICATIONS			SUB-	<u> </u>	LING
		<u> </u>	Pu	b. :	No.					Pub. Date		Patentee	- '	CLASS	CLASS		ATE
			_								_						
									F	ORBIGN PAT	ENT	DOCUMENTS					
	<u> </u>		. :	DOC	UME	NT	NUM	BER		DATE		COUNTRY		CLASS	SUB- CLASS	TRANS	LATION
	r.H.		1	1	2	2	8	9	0	8/2002	Eur	opean		нозм	13/39	X	
·.								口							,		
								П									
		OTH	ER I	DOCI	ME	NTS	(iı	nclu	ıdi	ng Author,	Tit	le, Date, Pertin	ent i	Pages,	Etc.)		L
	F.D.		Mo De	ham cod	mad er	M. Arc	Ma hit	nso ect	ur ure	et al., "I s", Proces	Desig	n Methodology fo of IEEE Confere es III-3085 - II	r Hi	gh-Spe on Aco	ed Itera	Spee	ch,
		•	Pr (J	anu	edi: ary	<u>19</u> 20	of (01)	14 ^{tr}	· I	nternation	al C	tectures for Hig onference on VLS	I Des	<u>sign</u> , p	bages 44	6-453	
	*EXAMINER: MPEP 609; Dr of this for	raw	Lin	e ti	hro	ugh	ci	tat	ior	n if not in	cor	er or not citation of the communication of the comm	on is	in co sidere	nforman d Inc	ce wid lude (copy

MAR 1 1 2004 5

Form PTO-14	49	U.	S.	DEI	PARTM	ENT	OF	SOMMERCE RK-OFFAREN		Y. DOCKET NO.		AL NO.			
									45565 10/634,746 APPLICANT						
INFO	TAMS	ION	DIS	CLC	SURE	CI	TATI	ON	•	Sung-Jin Park et	al.				
(Use s	seve	ral	she	ets	s if	ıec	essa	ry)		ING DATE ugust 6, 2003	GROU	JP		•	
								U.S. PATE	T DC	CUMENTS	1		,		
EXAMINER INITIAL		DOC	UME	ENT	NUMB	ER		DATE		NAME	CLASS	SUBCL		G DATE	
		T				Τ	T^{T}					ASS	APPRO	PRIATE	
			_	寸		†	\top			<i></i>	1				
		\vdash				╁	╀	 				 	ļ		
•			_			┸	1,					<u> </u>			
							1								
					\nearrow										
			\neq	1	-	╁	+				-	ļ <u></u>	<u> </u>	··	
······				\dashv	\dashv		+	 	\vdash			 			
			\dashv	\dashv		╁	+	<u> </u>	ļ						
	L					<u></u>	<u> </u>		Ŀ			L	l		
						PUI	BLIS	HED U.S. P	ATEN	r applications					
		Pub	. N	ю.				Pub. Date	:	Patentee	CLASS	SUB- CLASS		ING TE	
			• · ·												
	-						F	ORBIGN PAT	ENT :	DOCUMENTS					
		D	ocu	MEN	IT NUI	(BE	R.	DATE		COUNTRY	CLASS	SUB-	TRANS	LATION	
												CLASS	YES	NO	
F.10-		1	2	6	1 1	3	9	11/2002	EP		нозмі	13/29			
, ·		\perp	+	-	-										
	ОТНІ	ER DO	רו זיי	MEN	TS (i	nc1	1144	ng Author	Tit.	le, Date, Pertine	nt Pages	Etc. \			
F.D.		"Bi HTT	odi P:/	rec /WW	tona	.AB	hift	Registers	, ,	AL TUTORIAL/PART2			,		
		Gui No.	do 3,	Mas	era (et 8	al., -379	"VLSI Arc (Sept. 19	hite 99)	ctures for Turbo	Codes", 1	EEE Inc	., Vo	. 7,	
		War	ren hit	J.	Gros	ss o	et a Imp	l., "Diffe Dlementation	renc	e Metric Soft-Out pages 1-8 (Sept.	put Detec 2001).	ction:		·	
		N. Reg	Skl ist	avc	s et Archi	al te	., " ctur	A New Low e", <u>VLSI D</u>	Powe esig	r and High Speed n Laboratory, (Ju	Didirecti ly 2001)	onal Sh	ift		
*EXAMINER:	Ini	tial	if	ci	tatio	n (cons	idered, wh	ethe	r or not citation formance and not	is in co	onforman	e wit	h	
of this form	ı wi	th n	ext	CC	mmuni	cai	ion	to applic	ant	TOTHIBITICE GIRD HOC	considere	a. Inc.	tuae c	:ору	

SP 2 3 2004 55

23449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT

ATTY. DOCKET NO. 45565	SERIAL NO. 10/634,746	_
APPLICANT Sun-Jin Park , et al.		_

		(Use se	veral sheets if necessar	ry)	FILING DATE August 6, 2003				Assigned		
				II C. D.				-B			
			T	· ,	tent Documents	· ·	T=	I			
		ļ	Patent No.	Date	Patentee	Class	Sub-class	Filin	g Date		
		ļ		<u> </u>				<u> </u>			
		ļ									
		<u> </u>		ļ <u>.</u>		<u> </u>	<u> </u>	[
		<u> </u>						<u> </u>			
		1									
								-			
		<u> </u>									
									-		
		1									
•			Pul	blished U.S	S. Patent Application						
		T	Patent No.	Pub. Date	Patentee	Class	Sub-class	Filing	g Date		
						0.000	1 220 0.200		5 2 410		
					7.444						
				<u> </u>		L		L			
			Foreign Patent	Document	ts or Foreign Patent A	nnlicat	ione				
		l			o. roiga ruonoix	ppinear	T	Eng	glish		
		1.		İ		1		- Abs			
	^^	'	Document No.	Pub. Date	Country or Patent Office	Class	Sub-class	Yes	No		
\overline{F}	T.		1261139	11-2002	EPO			X			
\neg	10										
									1		
_				1							
	·								<u> </u>		
		<u> </u>	I	·		1			L		
	_	Other			rthur, Title, Date, Per						
/	$\bigcap \Lambda$				incent C., Gulak, P. Gleni						
V	11	1	Output Detection	n: Architect	ture and Implementation"	pp. 1-8	figure 7, Se	ptemb	er		
1	(K) *		2001.								
	+ -	-	Sklavos N Kite	os P Zem	as, N., & Koufopavlou, C	. "A NI	ew I ow Do-	Wer or	d high		
					gister Architecture", figu				o mgn		
	1		Masera, G., et al.	, "VLSI Ar	chitectures for Turbo Cod	les", IEI	EE Transacti	ions or	1		
	I	1			(VLSI) Systems, IEEE I						
	1										
			pp. 369-379, Sep			,		,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,			

^{*}EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw Line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.